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(71) Applicant (for all designated States except US): MELEXIS NV [BE/BE]; Microelectronic Integrated Systems, Rozendaalstraat 12, B-8900 Ieper (BE).

(72) Inventor; and

(75) Inventor/Applicant (for US only): DE WINTER, Rudi [BE/BE]; Corbiestraat 9, B-3550 Heusden-Zolder (BE).

(74) Agent: HILL, Richard; Wilson Gunn Skerrett, Charles Street, 148/9 Great Charles Street, Birmingham B3 3HT (GB).

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(54) Title: SINGLE PIN MULTILEVEL INTEGRATED CIRCUIT TEST INTERFACE

(57) Abstract: An integrated circuit comprises one or more integrated circuit elements which may interact with other circuitry via one or more input/output pins. In the present invention the circuit elements include and interface element for interfacing with external test circuitry. The interface element communicates with the external test circuitry via a single input/output pin dedicated for testing.